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Peer Review

U.S. DEPARTMENT OF
ENERGY | OFFICE OF
ELECTRICITY

IPS Hardware Prototype Development

PRINCIPAL INVESTIGATOR:

Dr. Hui "Helen" Li, Professor, FSU,

Co-PIs:

Dr. Yuan Li, Assistant Professor, FSU

Dr. Jinyeong Moon, Assistant Professor, FSU

PROJECT SUMMARY

The objective of this project is to develop and validate an intelligent power stage (IPS) with advanced features to improve the robustness and reliability of grid-tied converters interfacing renewable energy source and energy storage elements. The prototype will be a 3-phase interleaved DC/DC stage with a 500V-1kV DC input and a 3-phase DC/AC stage rated at 50 kW and 480 Vac. The proposed advanced features will be verified on the developed IPS hardware.

Innovations

✓ Active Gate Driver (AGD)

- Control dv/dt and switching loss based on load current & device temperatures.
- Integrate fault/protection with active gate driver functions.

✓ Prognosis & Diagnosis (P&D)

- Integrate device aging prognosis and diagnosis of gate driver status based on gate current sensing.
- Low-cost and anti-noise implementation.

✓ Control and Communication

- Enhanced EMI-immune IPS control with high A/D sampling CM noise rejection ratio.
- up to 50Mbps bidirectional all fiber optic-based communication among SUPER, IPS control and gate drivers.

✓ LVRT/ZVRT functions

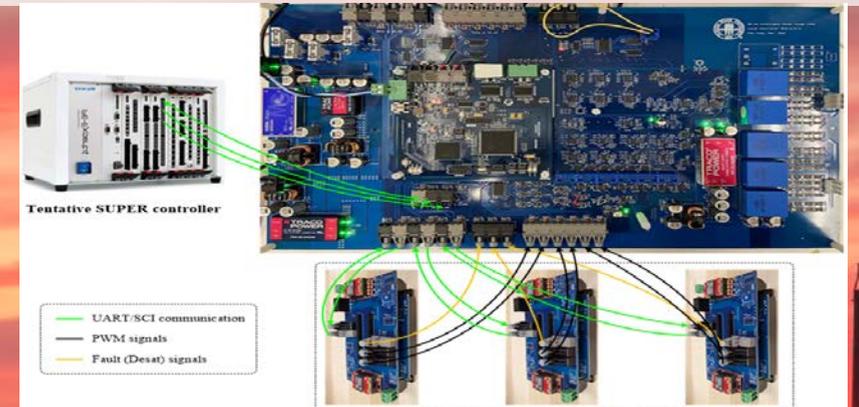
- Low-latency hardware-based approach to suppress inrush current.
- Mitigate transient inrush current from 312% \rightarrow 155%.

✓ Self-sustained Auxiliary Power Supply (APS)

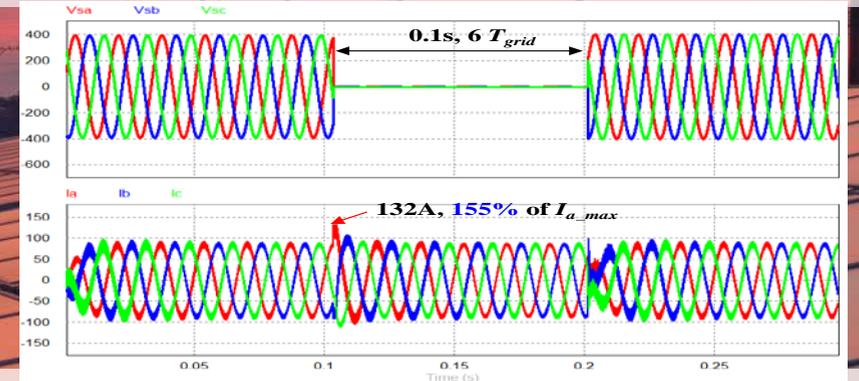
- Dual inputs from DC or AC bus.
- Enhanced common-mode noise immunity.



Integrated and intelligent gate driver: AGD + P&D



EMI-immune Control and fiber optic communication



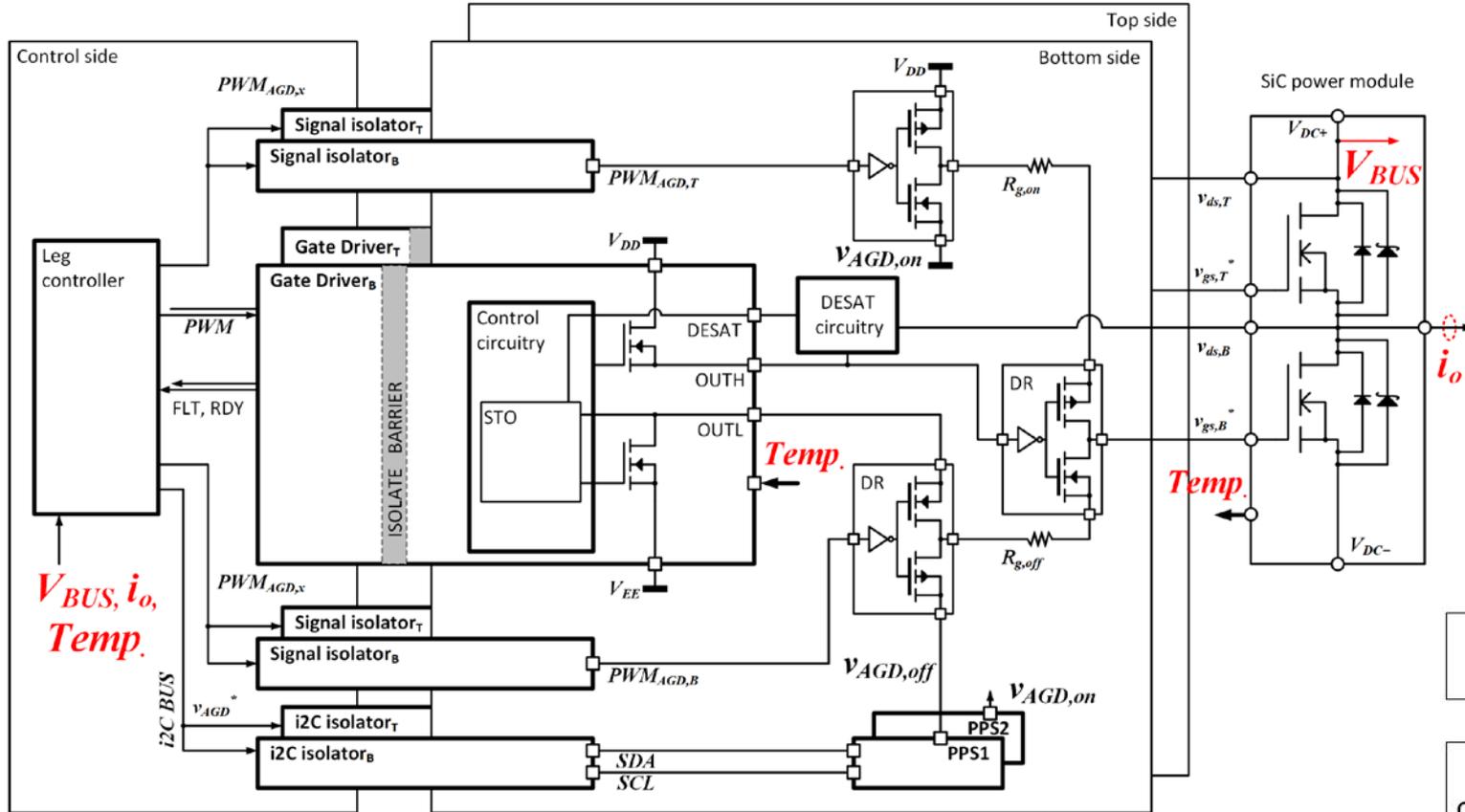
ZVRT control



Self-sustained APS

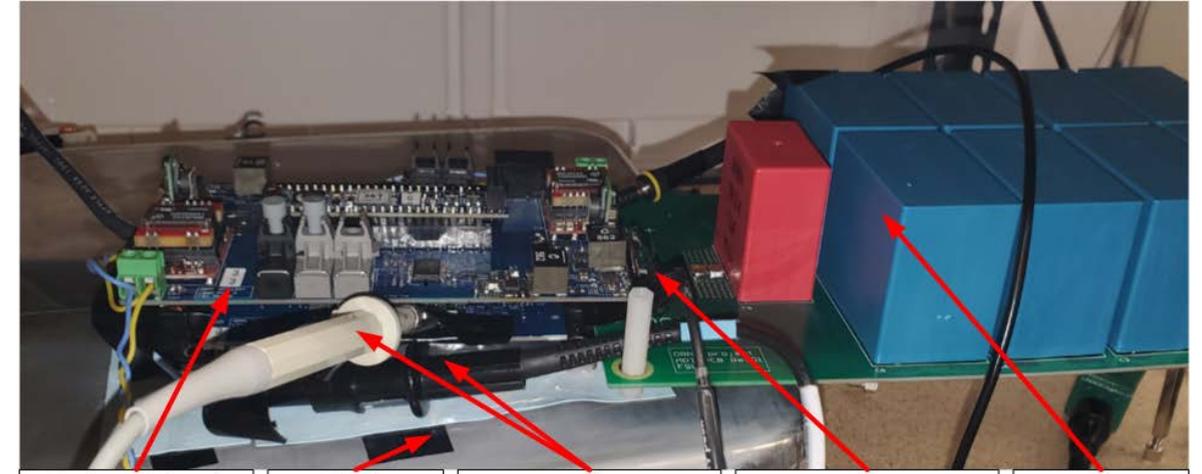
AGD Function and Experimental Verification (1/2)

➤ Proposed AGD circuit

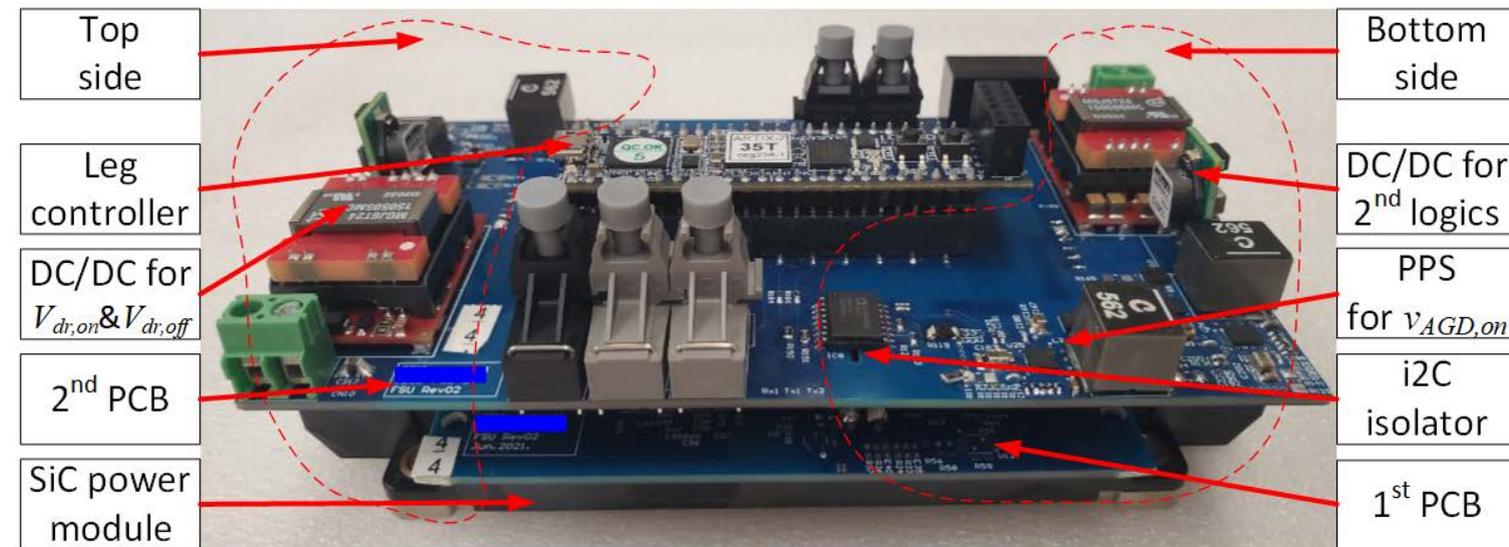


- Control dv/dt and switching loss.
- Integrated AGD circuit with fault/protection functions.
- Optimized circuit design for precise AGD control.
- AGD control based on load current and device temperature.

➤ Hardware prototype

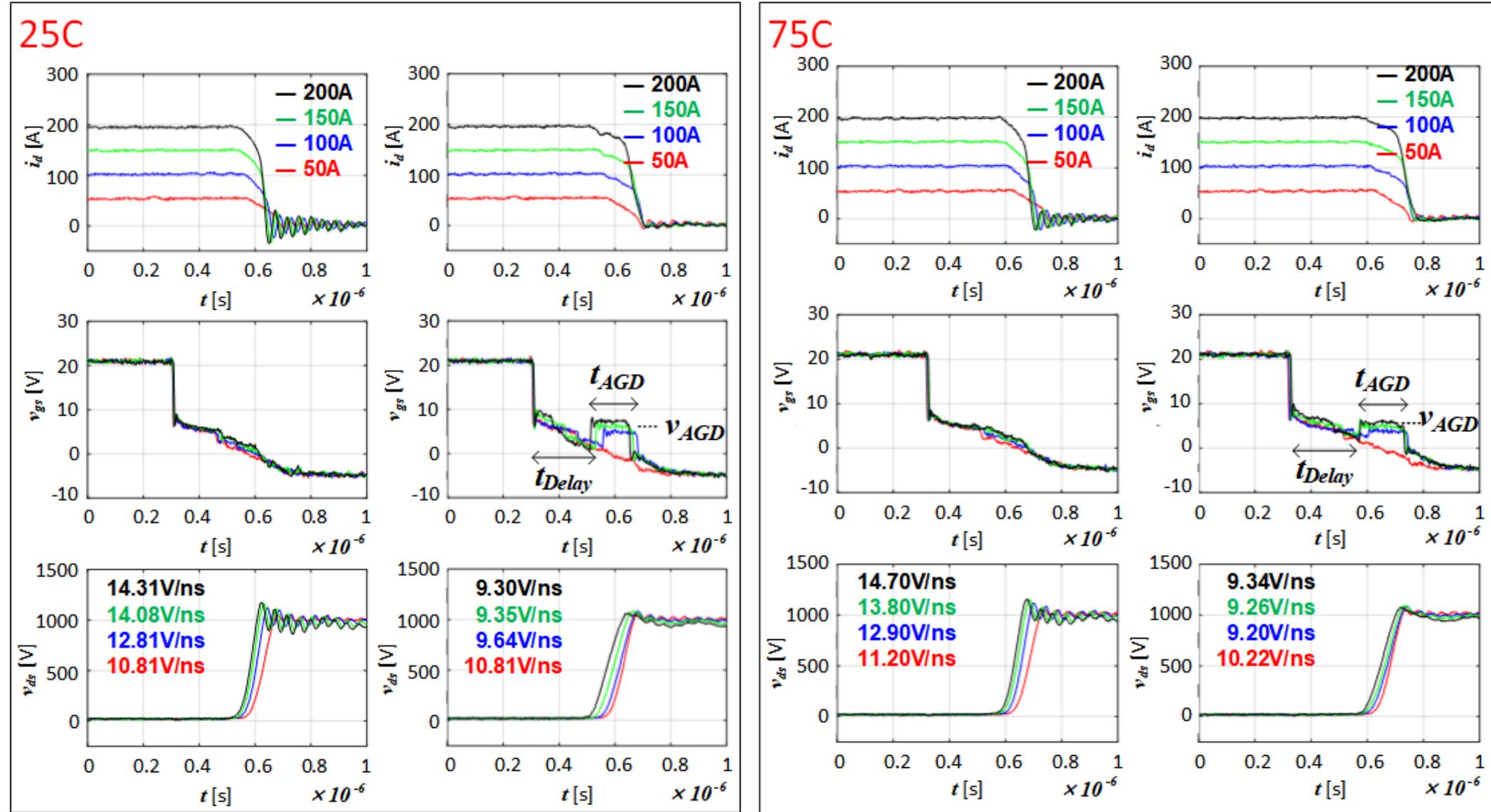
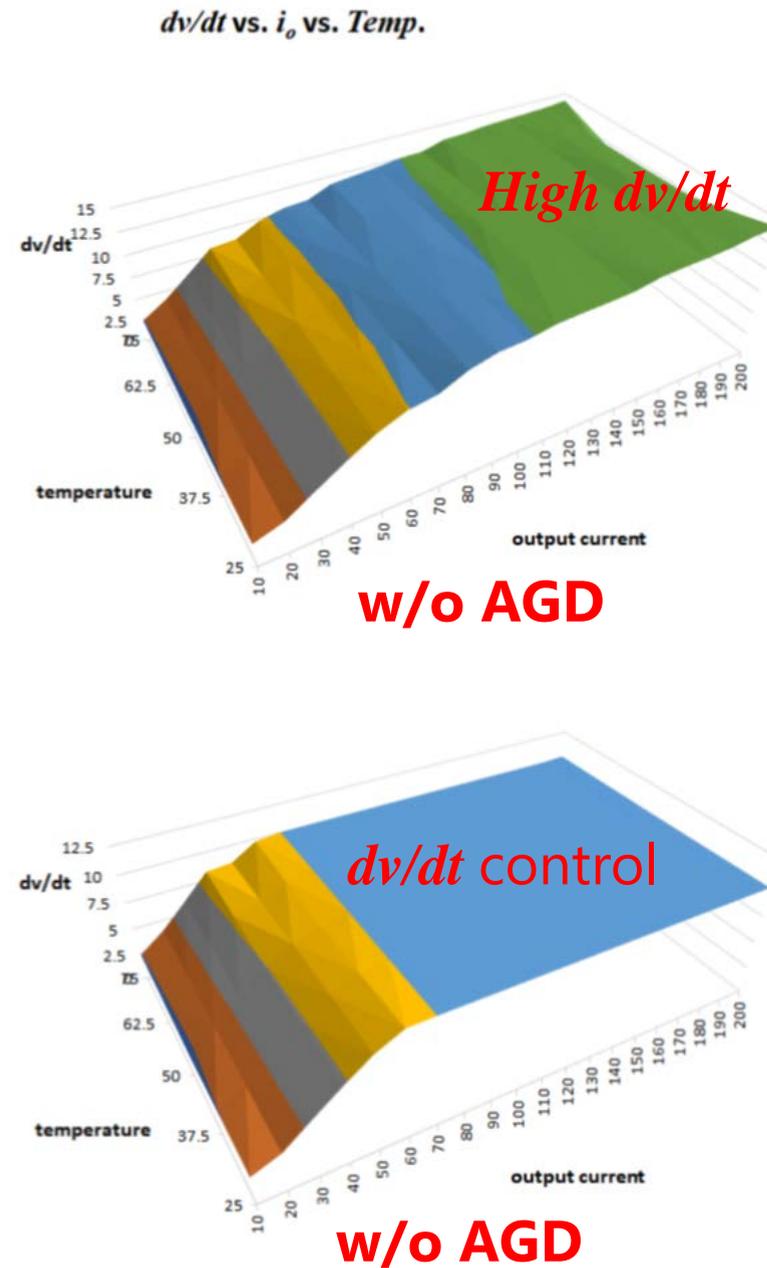


Integtrated Gate driver Hot plate v_{gs} & v_{ds} measurement i_d measurement DC-link



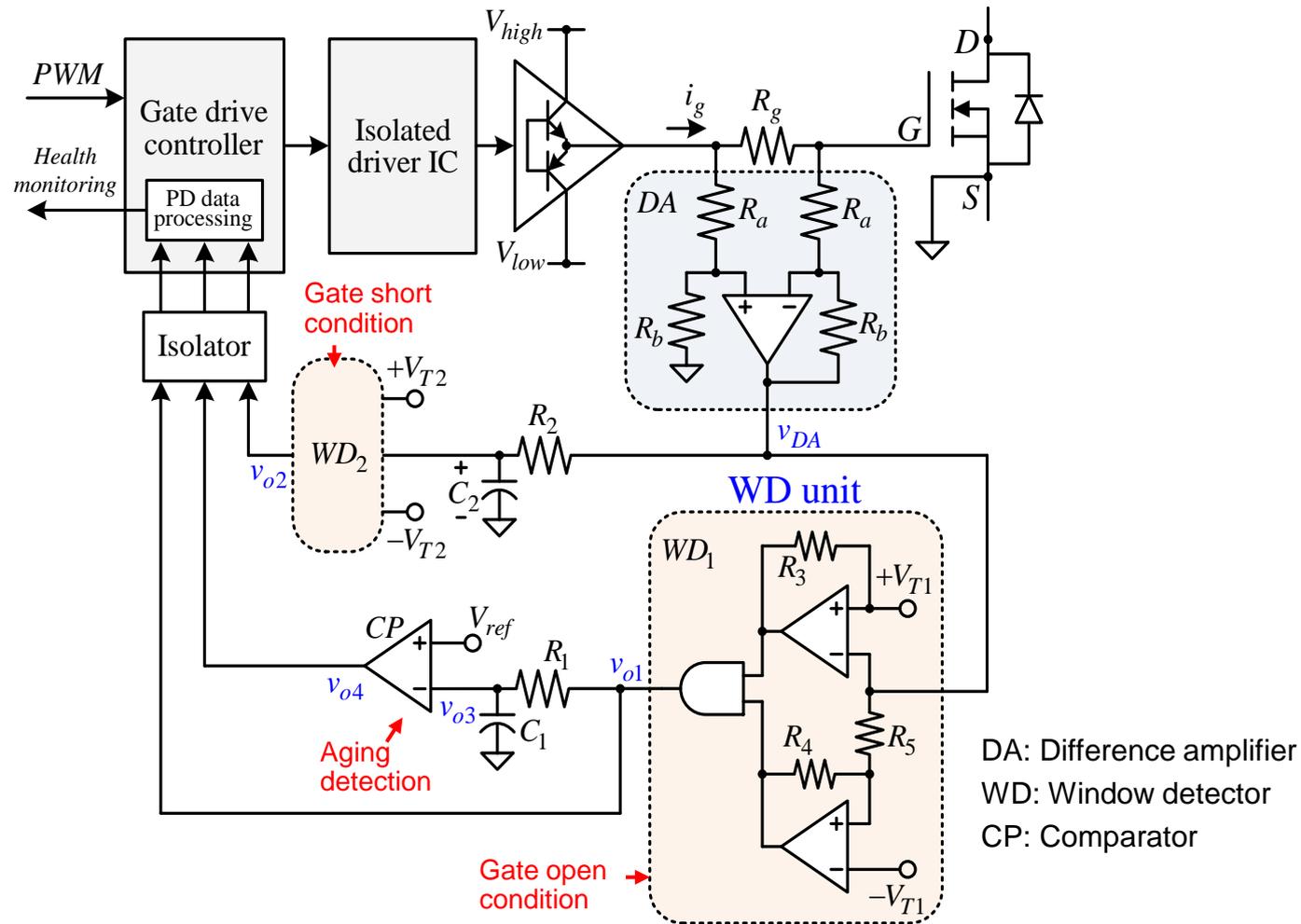
AGD Function and Experimental Verification (2/2)

dv/dt controlled under different load current and device temperatures

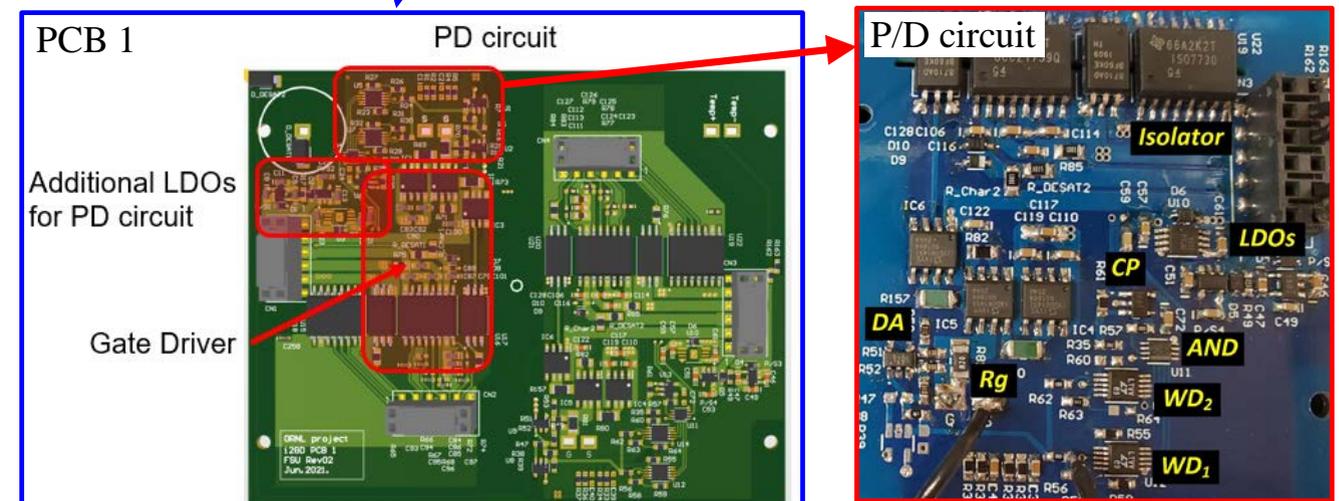


P&D Function and Experimental Verifications(1/2)

➤ Proposed P&D circuit



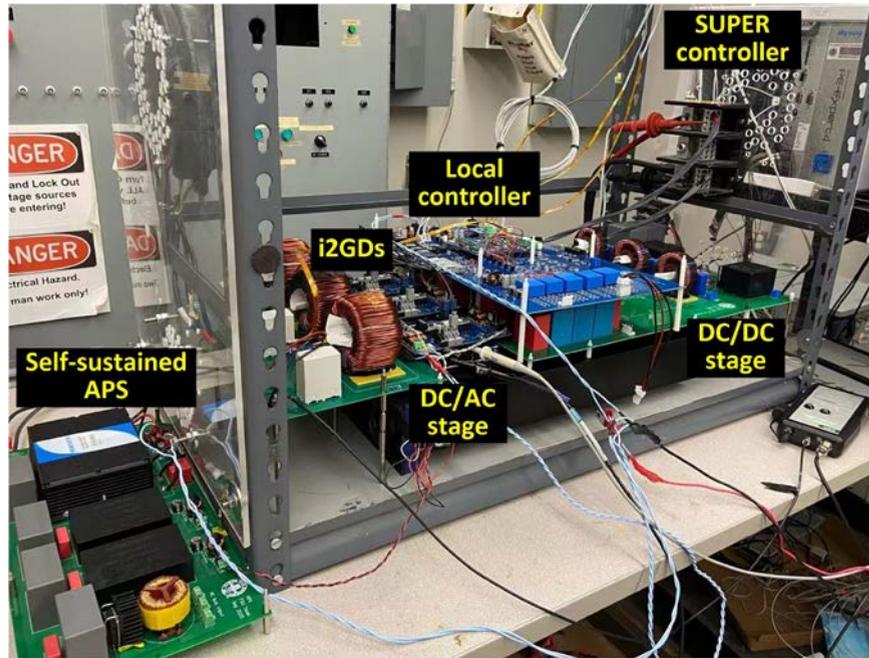
➤ Hardware prototype



- Diagnose status of both power device and gate driver (GD) based on monitoring gate current
- Diagnosis of gate open/short circuit conditions, connection verification, and GD board fault
- Prognosis of device aging → generating early warning signal

P&D Function and Experimental Verifications (2/2)

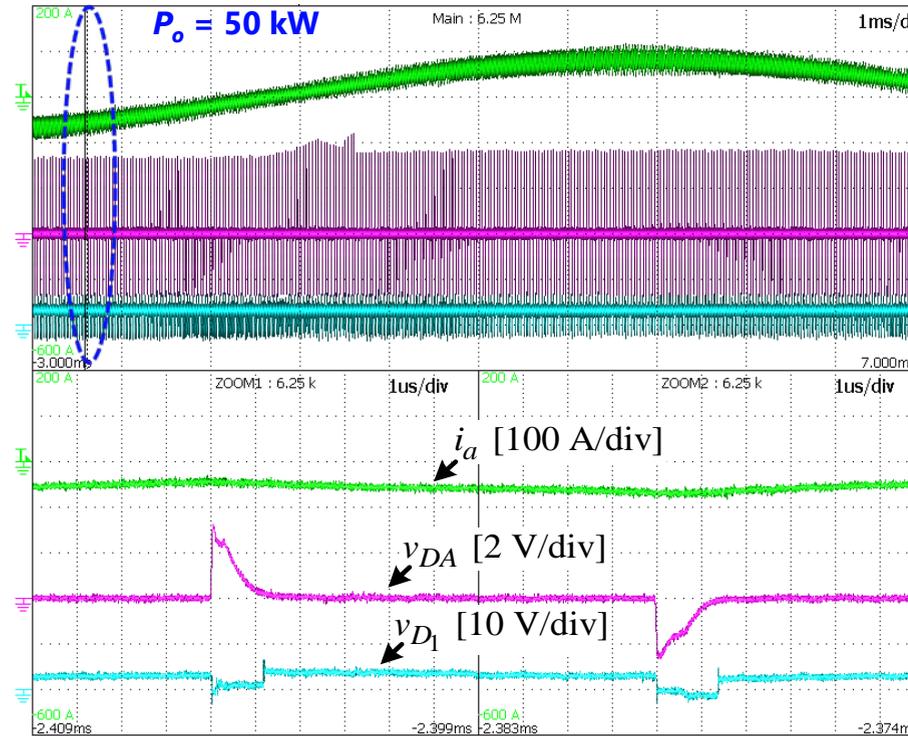
➤ Inverter based verification



Specification:

- $V_{dc} = 1 \text{ kV}$
- $V_{ac_LL_rms} = 480 \text{ Vrms}$
- $P_o = 50 \text{ kW}$
- $f_{sw} = 30 \text{ kHz}$
- $L_{DM} = 300 \text{ uH}$

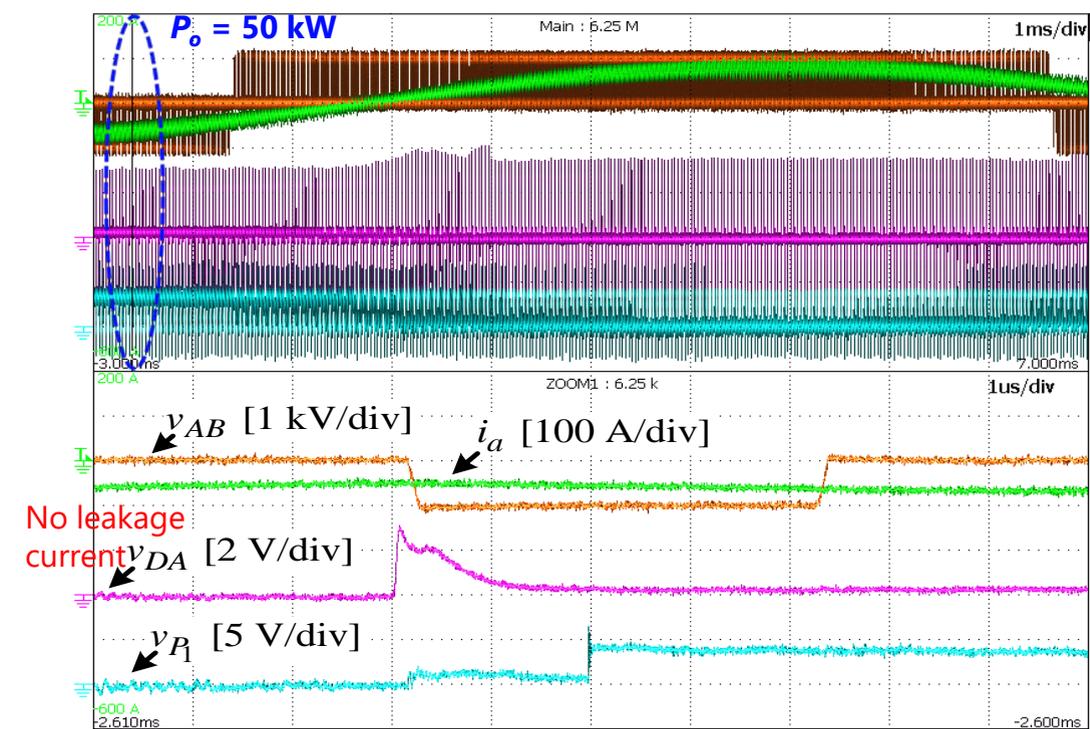
✓ Diagnosis verification



phase current (i_a): Green v_{DA} : pink v_{D1} : Blue

- When gate open: no gate current
→ v_{D1} becomes logic "1"
- When gate short circuit: continuous gate short current
→ v_{D1} becomes logic "0"

✓ Prognosis verification



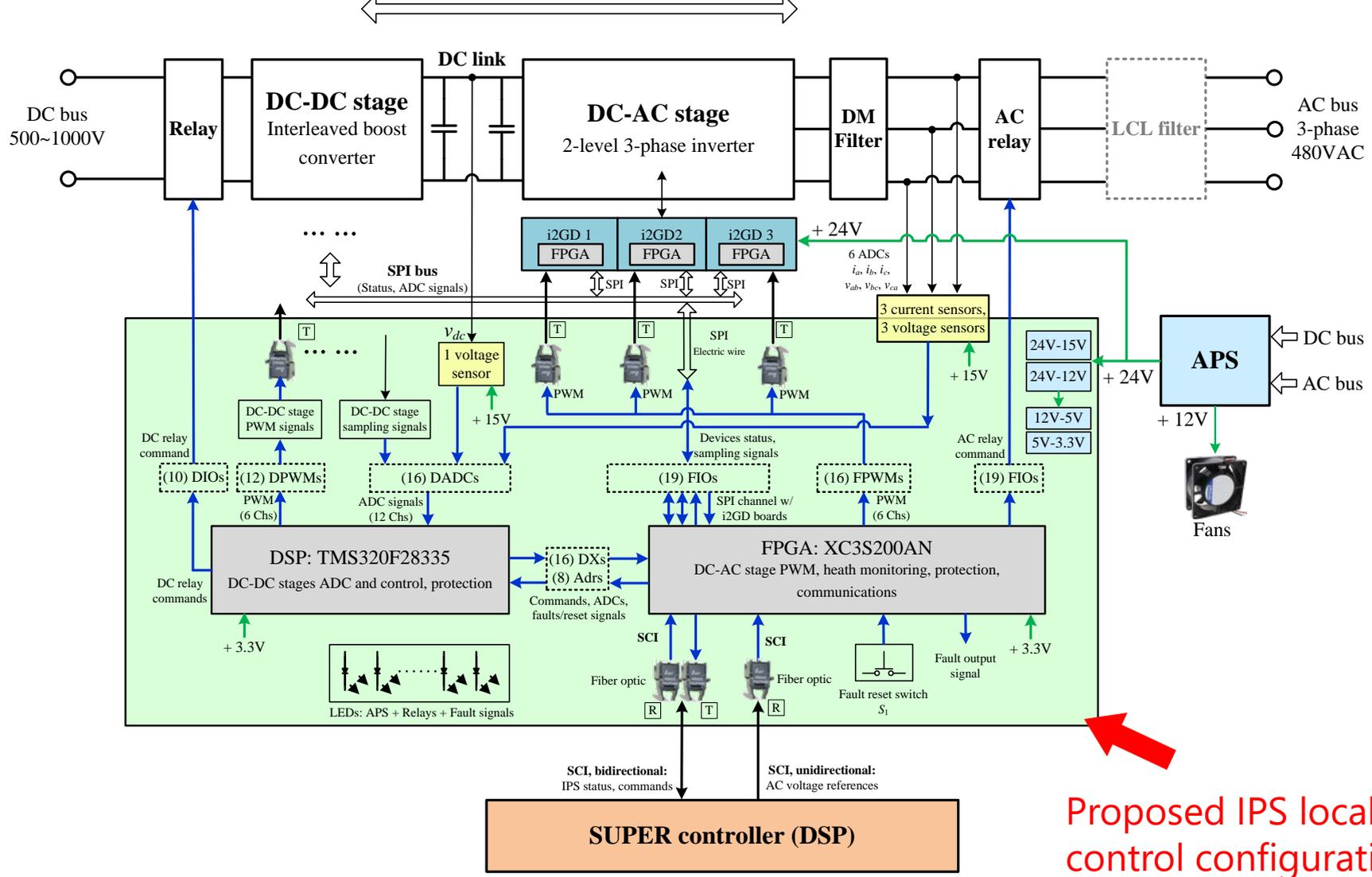
phase current (i_a): Green v_{DA} : pink, v_{P1} : Blue

- When gate leakage current is zero
→ v_{P1} is logic "0", device not aged;
- When gate leakage current $> 200 \text{ mA}$
→ v_{P1} becomes logic "1", device aged;

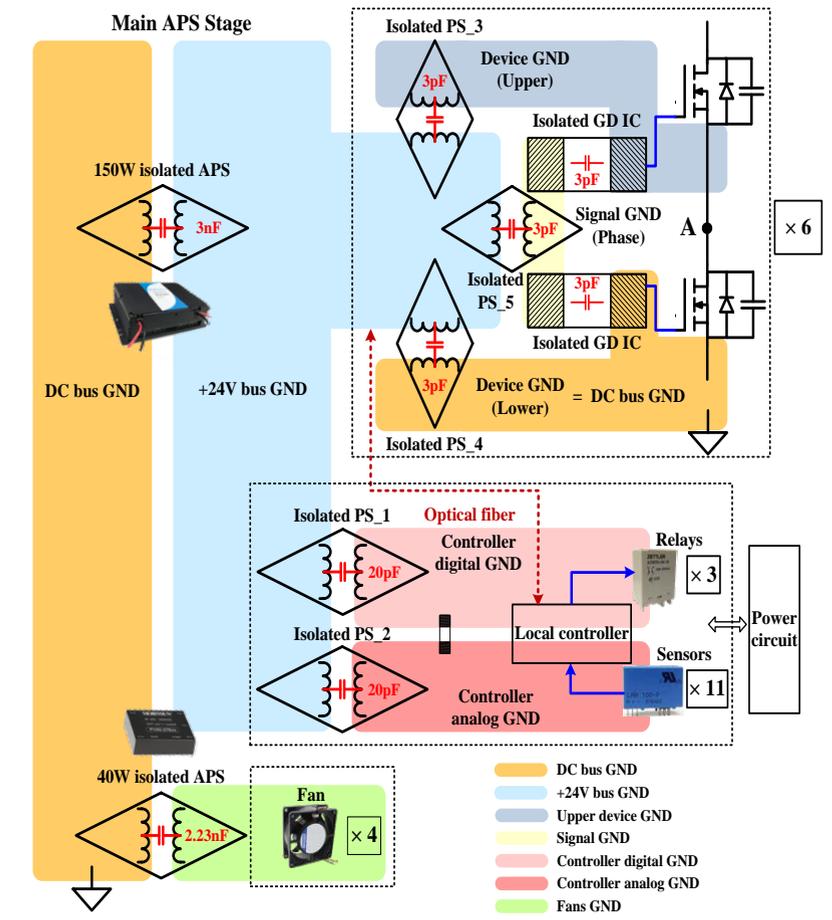
IPS Control with Enhanced EMI-immunity

Intelligent Power Stage (IPS)

Bi-directional power flow



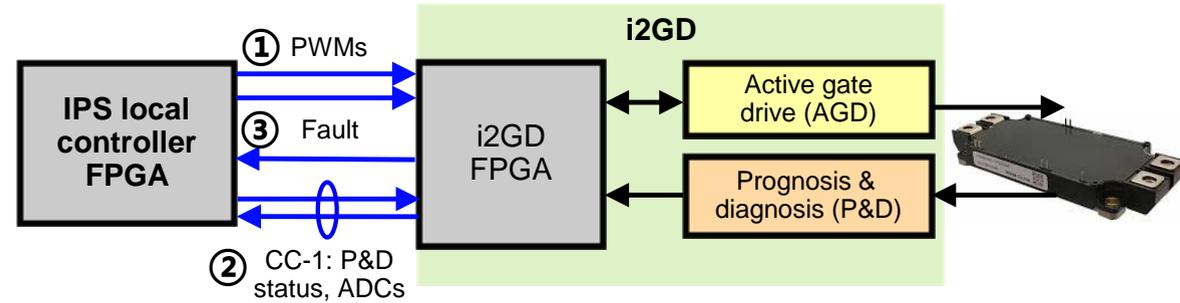
Proposed IPS local control configuration



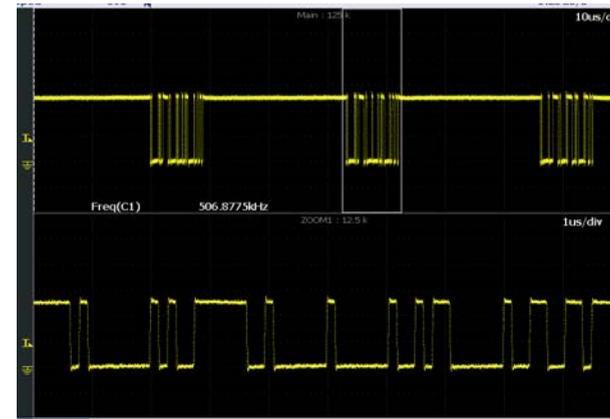
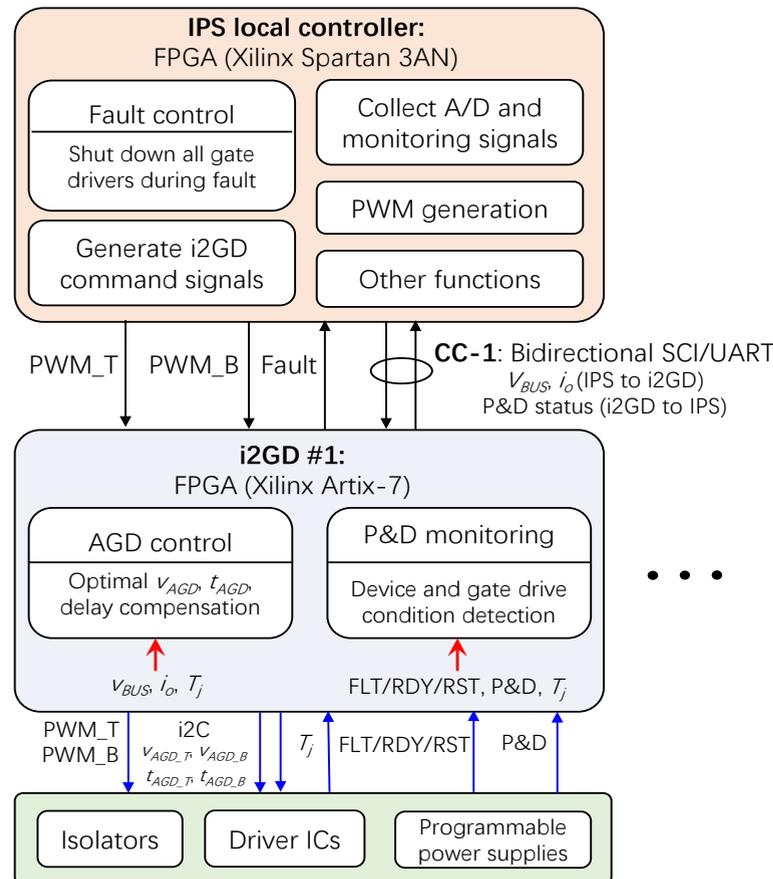
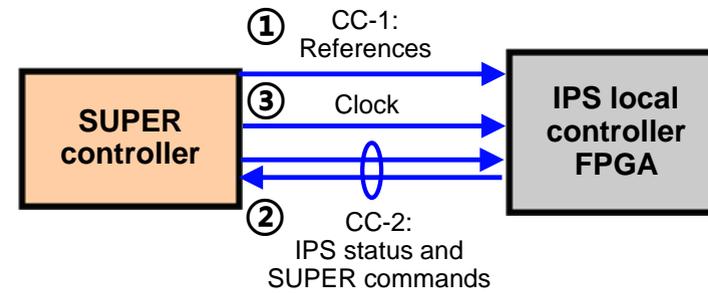
Enhanced EMI-immunity design to reduce parasitic capacitors

IPS Communication with SUPER and Gate Drive

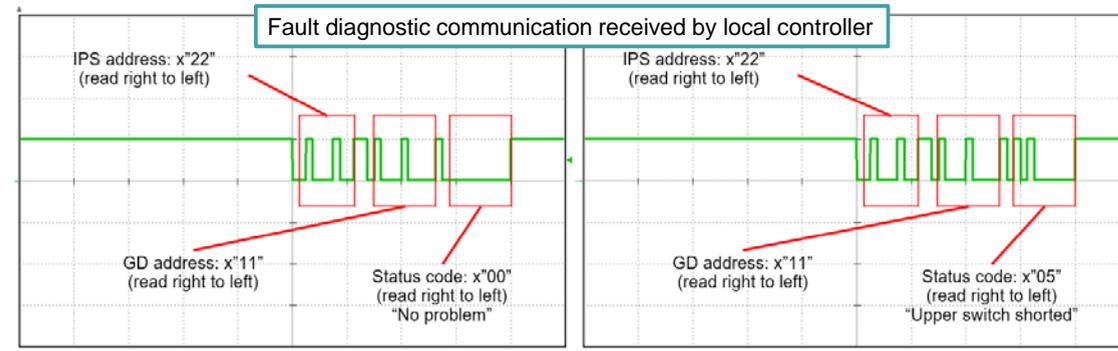
Communication between IPS control and GD



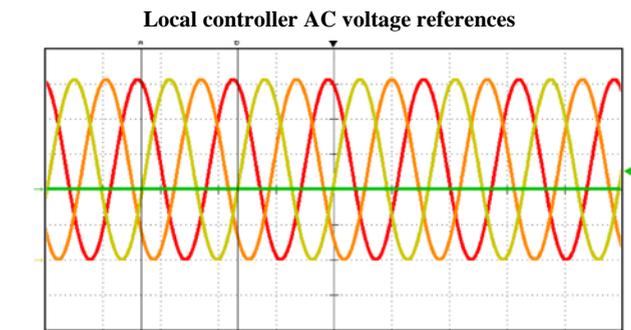
Communication between SUPER and IPS control



Communication validation of AGD function



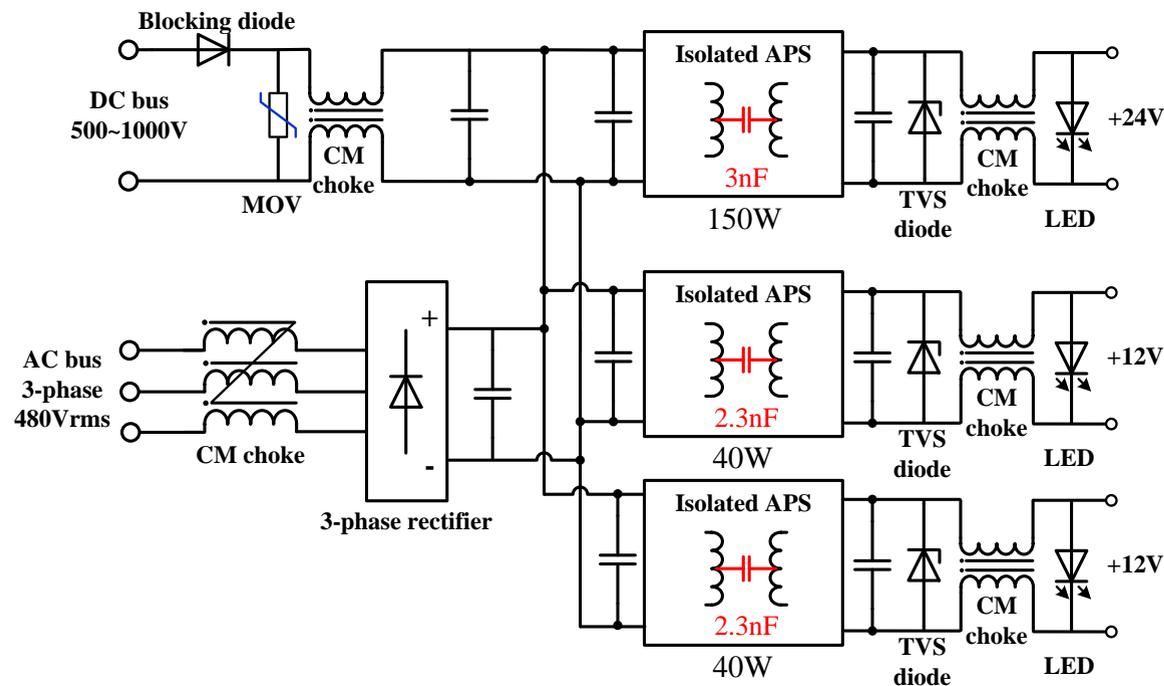
Communication validation of P&D status



Communication validation of PWM signals

Self-sustained Auxiliary Power Supply (APS)

➤ Proposed APS circuit

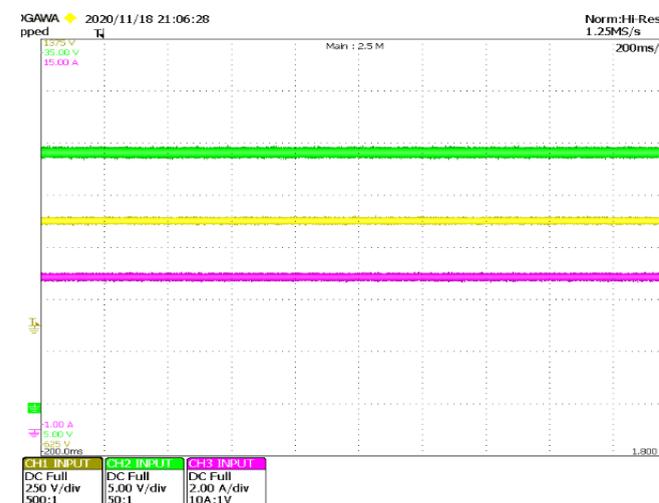


➤ Prototype



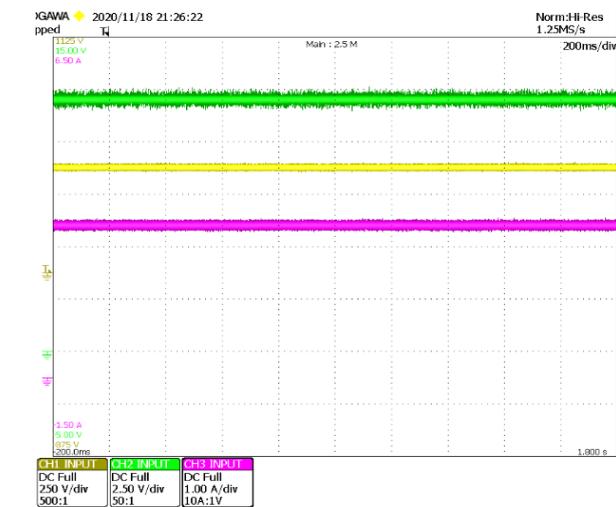
➤ Experimental results

- Dual input from DC or AC buses
- Input dc voltage range: 250V~1200V
- +24V bus: 150W, +12V bus: 40W×2
- Efficiency: ~90%



+24V bus waveforms@150W

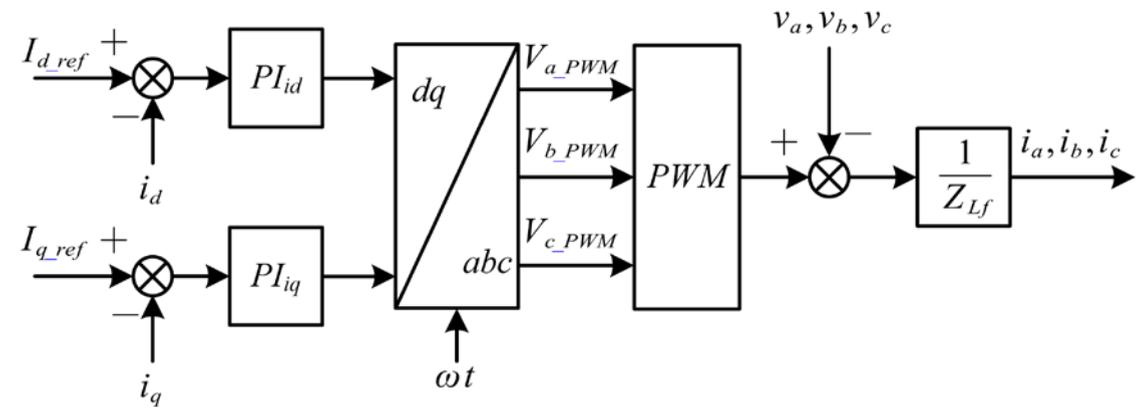
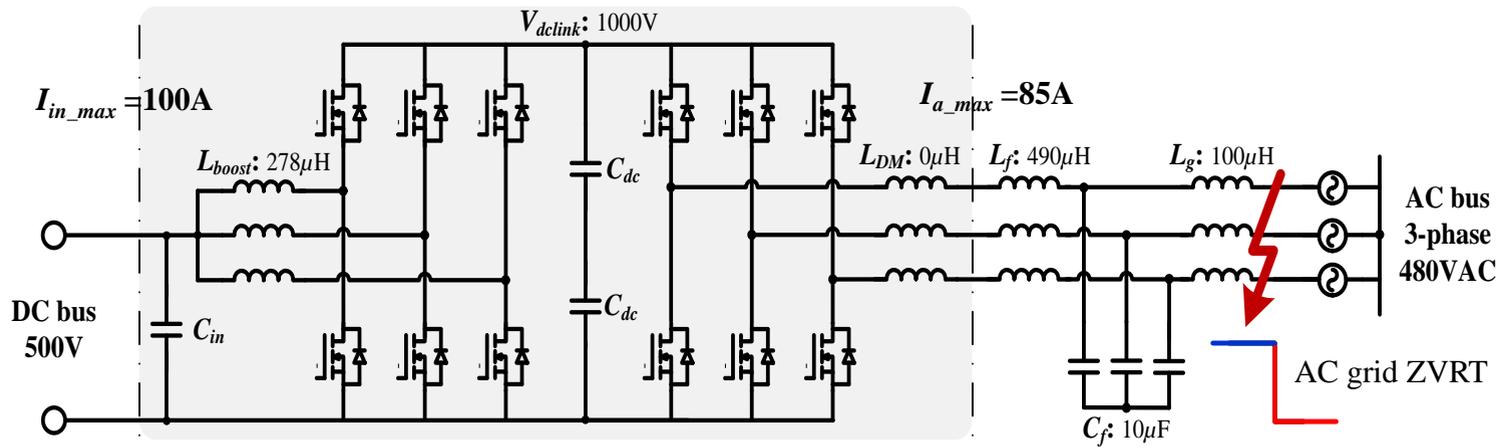
V_{+24} : 24V
 V_{in} : 500V
 I_{+24} : 6A



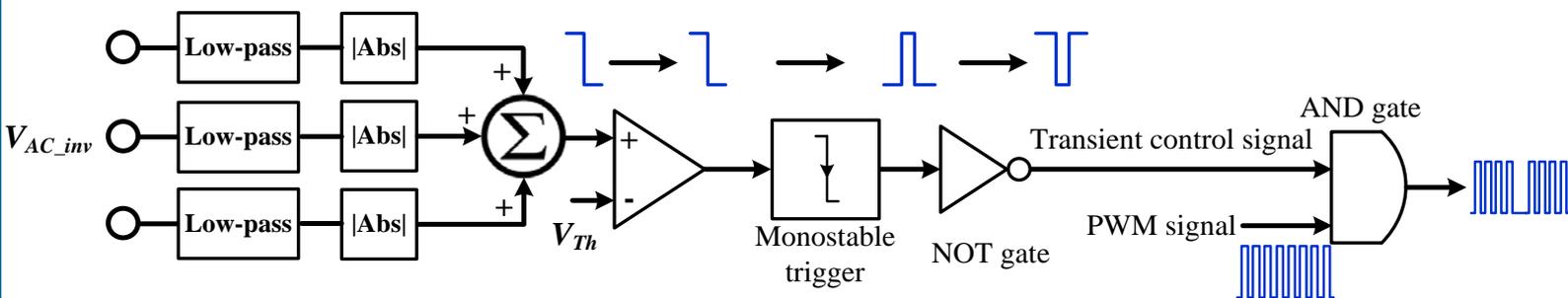
+12V channel waveforms@40W

V_{+12} : 12V
 V_{in} : 500V
 I_{+12} : 3A

Zero-voltage Ride Through (ZVRT) Control

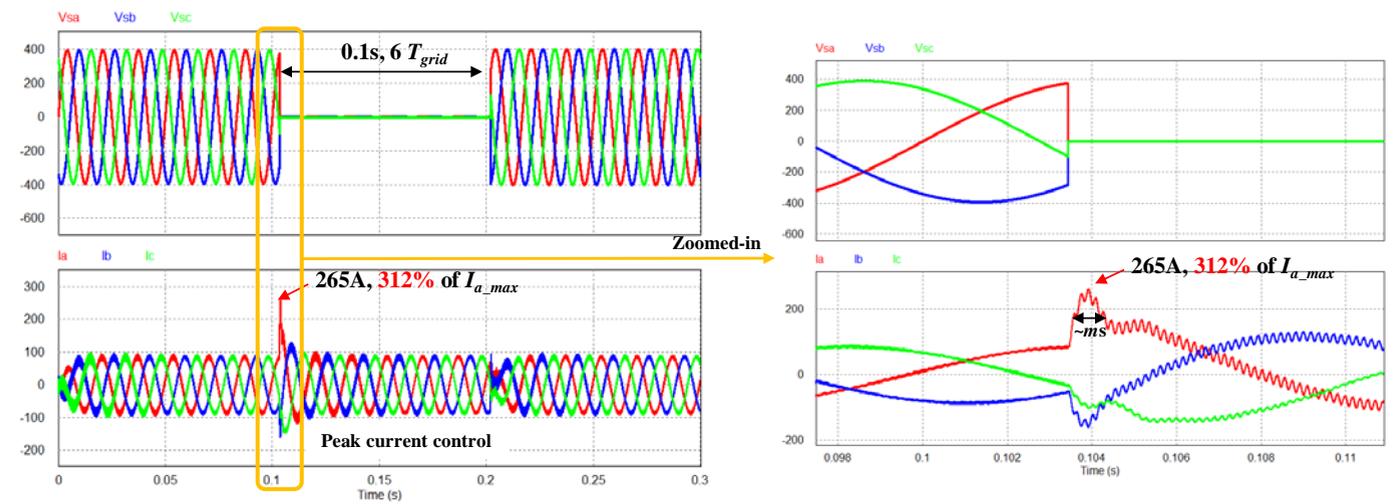


Tradition ZVRT control

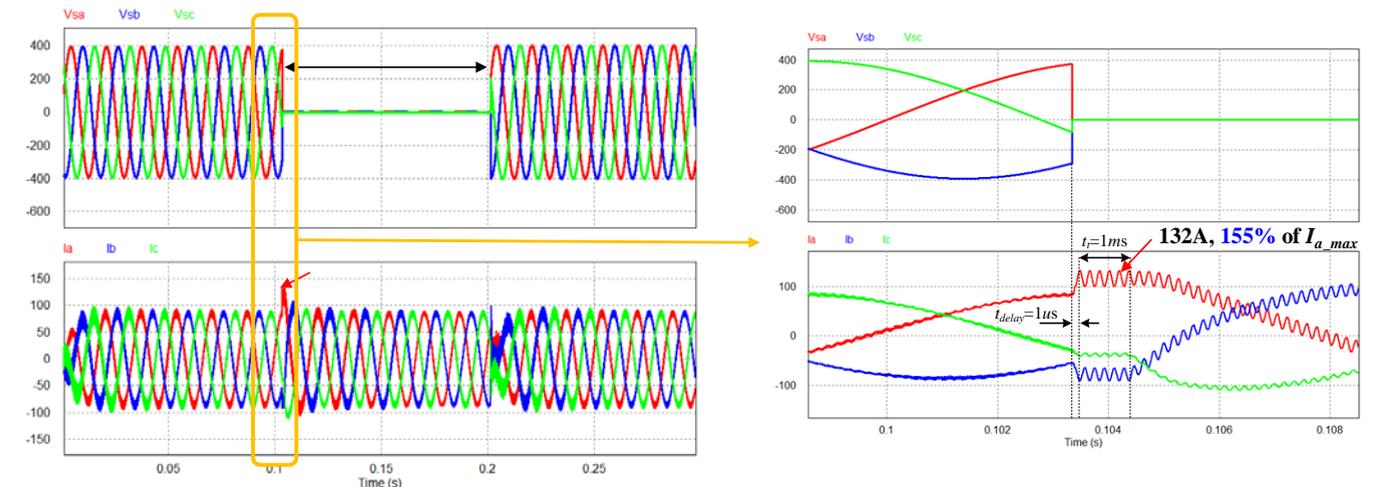


Proposed hardware-based control to mitigate inrush current

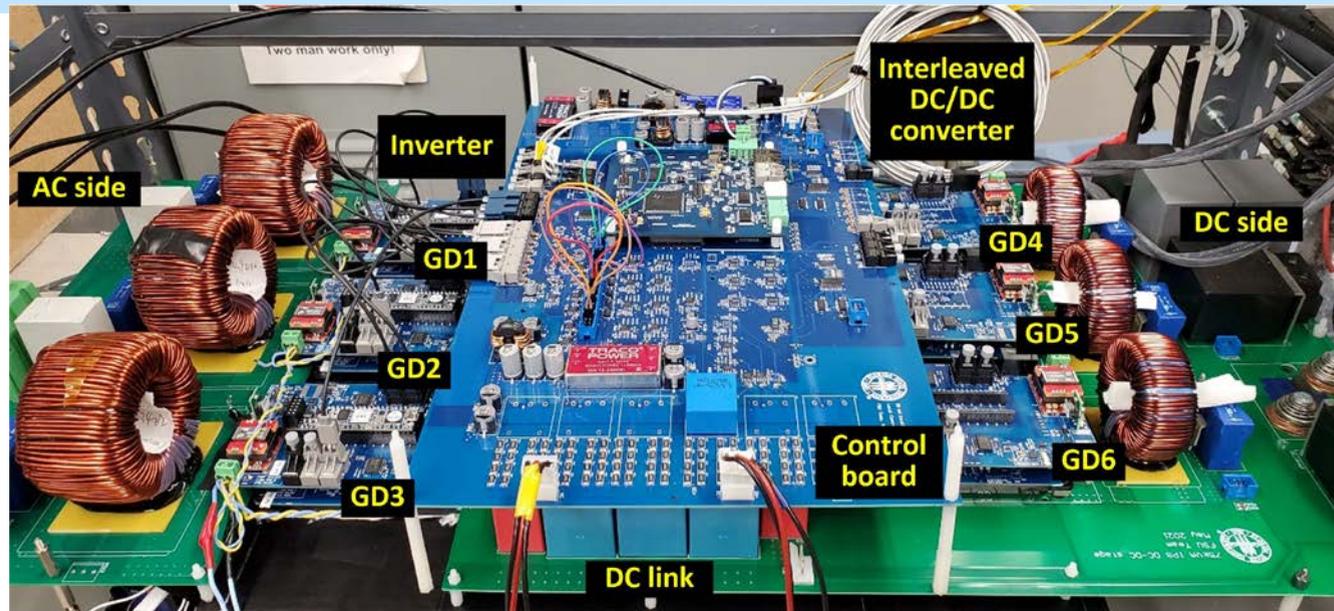
with tradition ZVRT control



with proposed ZVRT control

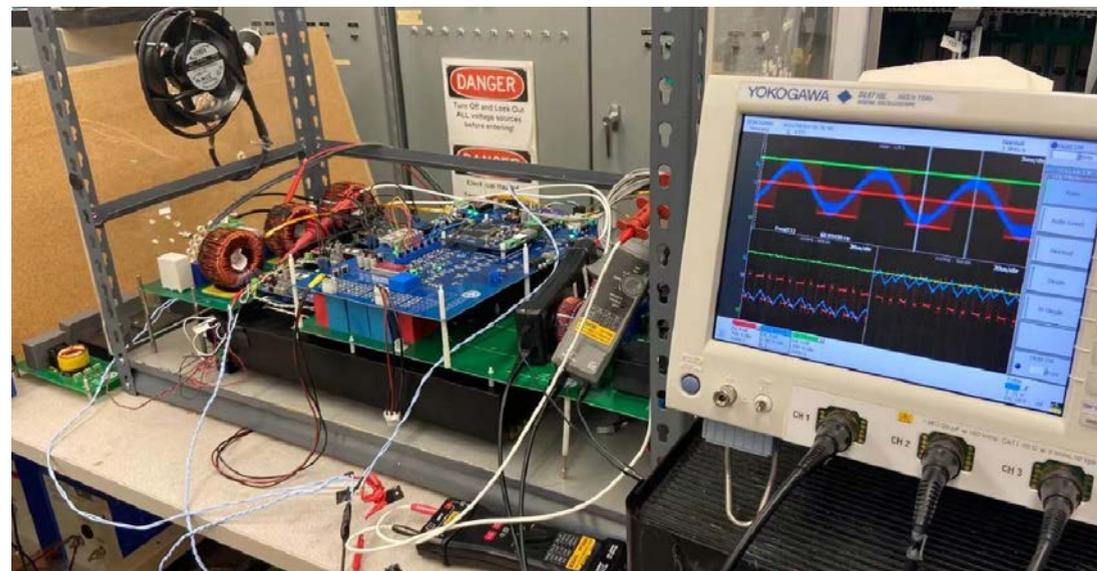
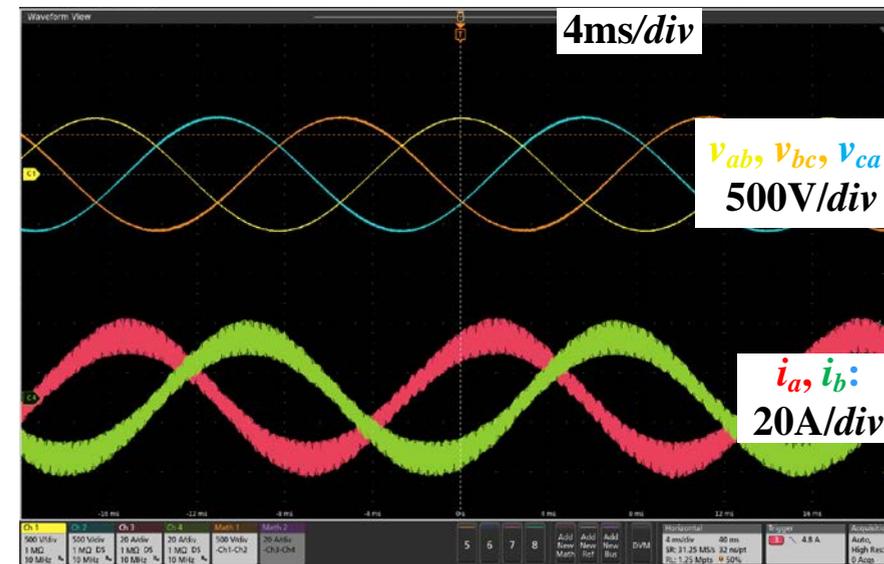


Grid-tied Closed-loop Experimental Results



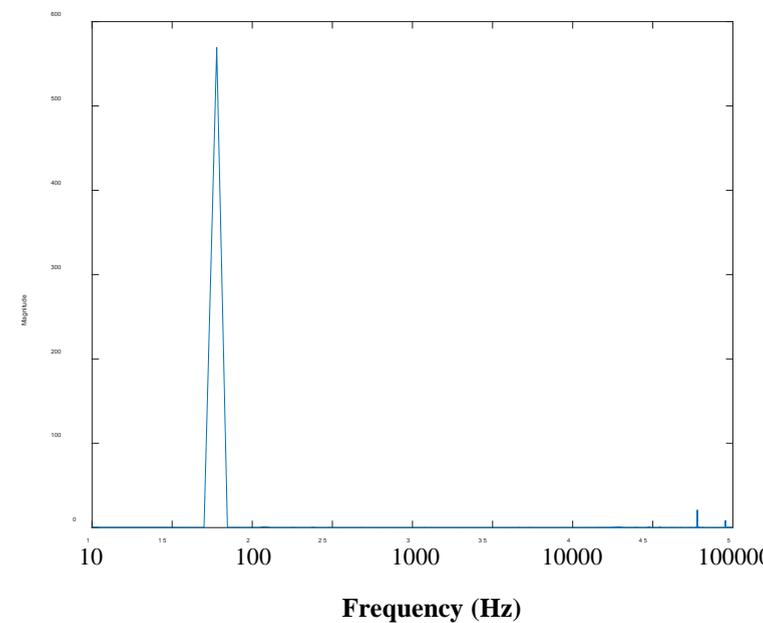
Hardware prototype

Measured voltage and current waveforms

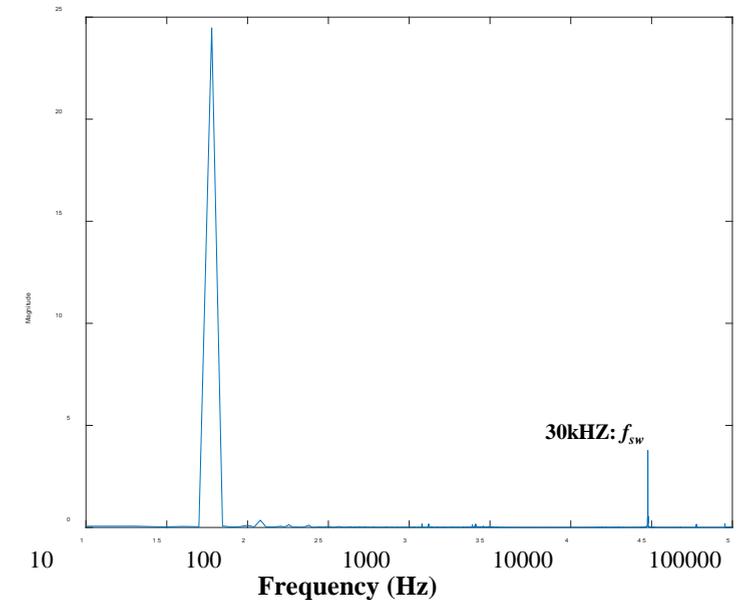


Experimental testbed

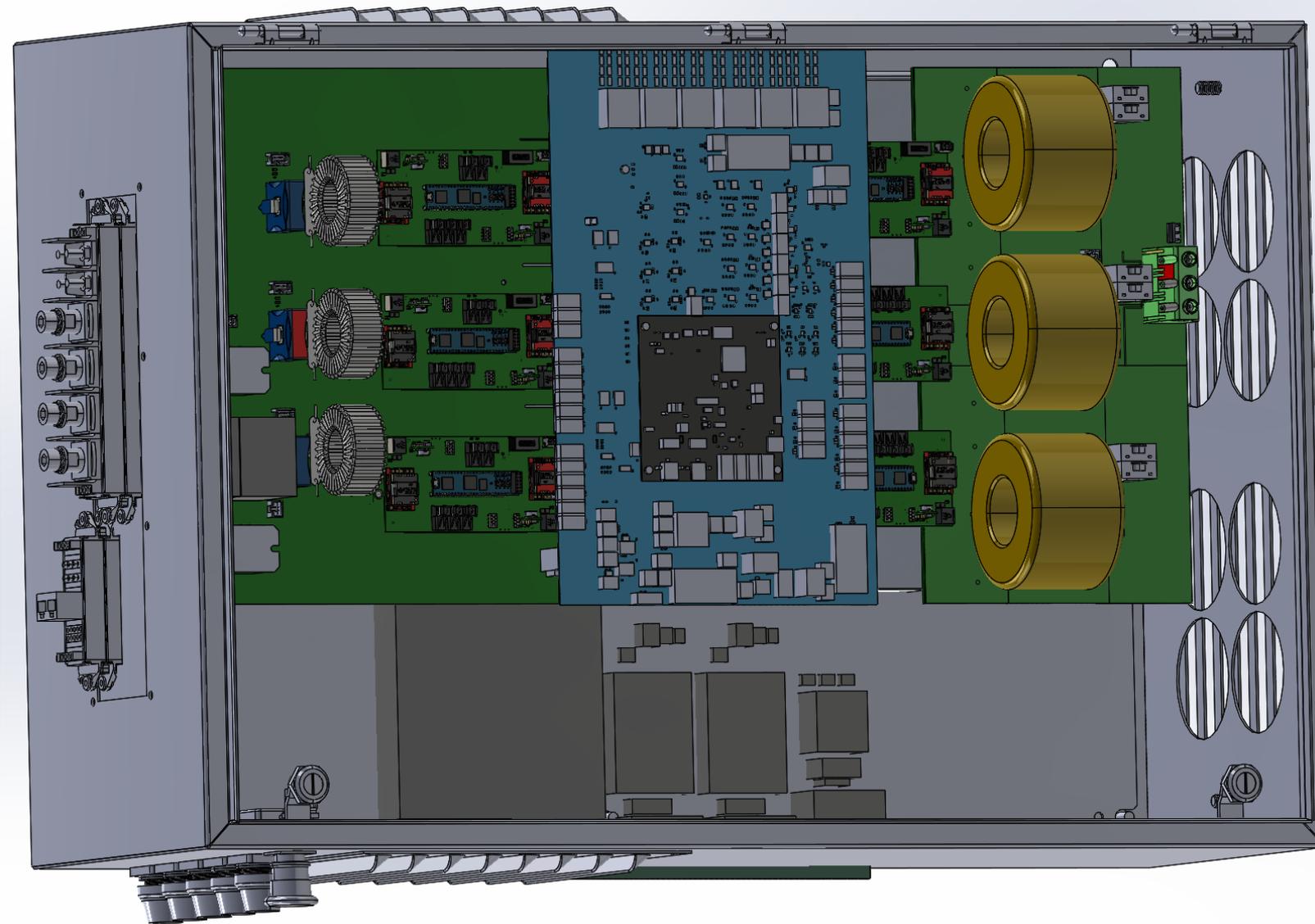
Grid voltage FFT



Grid current FFT ($i_{THD} = 1.65\%$)



IPS with the Standardized Enclosure



3D CAD/picture of the IPS with the standardized enclosure: 36" x 24" x 12"

Milestone Update

BP1 Milestones

Milestones	% Progress toward Completion
M 1.1 Intelligent gate drive, APS, DC/DC stage and DC/AC stage design	100%
M 1.2 Simulation verification of design	100%
M 1.3 Local controller, APS and gate drive hardware fabrication	100%
M 1.4 DC/DC and DC/AC power stage hardware fabrication and subcomponent demonstration	100%

BP2 Milestones

Milestones & Subtasks Description	Schedule	% Progress toward Completion
M 2.1 Closed-loop experimental validation of IPS DC/AC stage	2021.9.16-2021.12.15	100%
M 2.2 IPS system-level advanced features validation	2021.12.16-2022.3.15	30%

Accomplishment Summary and Future Work

- 50kW IPS hardware built and tested at 50kW in open-loop mode.
- Advanced features of AGD and P&D functions has been verified experimentally
- Grid-tied closed-loop experiments have been tested successfully
- The communication between SUPER and IPS local controller has been implemented and tested.

- The LVRT experiments, the communication between IPS controller and gate driver, the integration of DC/DC stage and DC/AC stage will be tested in 2022.

Impact/Commercialization

- Provide a general solution to improve reliability and resilient grid integration of renewable energy with storage.
- Apply not only to next generation WBG device based grid-tied power electronics but to traditional grid-tied power electronics as well.
- Enable the revolutionary approach to integrate renewable energy based on SUPER+IPS.

IP STATUS

NA.

Publications

- “An Intelligent Gate Driver With Self-diagnosis and Prognosis for SiC MOSFETs,” in *Proc. IEEE Energy Convers. Congr. Expo. (ECCE)*, 2021.
- “An Integrated Active Gate Driver for SiC MOSFETs,” in *Proc. IEEE Workshop on Wide Bandgap Power Devices and Applications (WiPDA)*, 2021.
- “SiC-Based Intelligent Power Stage with Device Prognostics/Diagnostics and ZVRT Capability for Smart Universal Power Electronic Regulators (SUPER) Application,” in *Proc. IEEE Applied Power Electronics Conference and Exposition (APEC)*, 2022.
- “An Integrated Active Gate Driver for Half-bridge SiC MOSFET Power Modules”, in *Proc. IEEE Applied Power Electronics Conference and Exposition (APEC)*, 2022.

Risks and Mitigation Strategy

- Supply chain shortage will delay the 2nd hardware unit development.
- Redesign the IPS to use available components but will be time-consuming.

THANK YOU

This project was supported by the Department of Energy (DOE) - Office of Electricity's (OE), Transformer Resilience and Advanced Components (TRAC) program led by the program manager Andre Pereira & Oak Ridge National Laboratory (ORNL)

Acronyms

SUPER: Smart Universal Power Electronic Regulator

IPS: Intelligent Power Stage

GD: Gate Drive

AGD: Active Gate Drive

P&D: Prognosis and Diagnosis

LVRT/ZVRT: Low-voltage ride through/zero-voltage ride through

APS: Auxiliary Power Supply

EMI: Electromagnetic Interference

CM: Common-mode